## Search Notes



Application/Control No.	Applicant(s)/Patent Under
	Reevamination

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Reexamination KUTARAGI ET AL.

Art Unit

Examiner Cloud, Joiya M

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## SEARCHED

Class	Subclass	Date	Examiner	
709	229, 217	01/05/2007	JC	
473	29	01/05/2007	JC	
725	6	01/05/2007	JC	

## SEARCH NOTES

Search Notes	Date	Examiner
EAST, US Patent, USPGPUB, DERWENT, JPO, EPO, IBM DB	01/05/2007	JC
101 CONSULTATION SPE W. VAUGHN	01/05/2007	JC
NPL GOOGLE SEARCH, IEEE XPlore	01/05/2007	JC
EIC FAST AND FOCUS SEARCH- search specialist Alyson Dill	01/05/2007	JC
consulted William Vaughn-RCE	05/21/2007	JC
EIC FAST AND FOCUS SEARCH-search specialist Byron Mimms	10/24/2007	JC
UPDATED SEARCH	10/27/2007	JC
UPDATED SEARCH	05/28/2008	JC

## INTEREPEDENCE CEARCH

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		
709	229,217	10/27/2007	JC		
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